

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-1027-02		SERIAL NO. <b>10/774, 371</b>	
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Y. TAKAHASHI et al			
<b>(1) of (2)</b>				FILING DATE February 10, 2004		GROUP <del>1773</del> <b>1762</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>	
<b>AB</b>	AA	5,738,927	04/1998	Nakamura et al			
	AB	6,080,476	06/2000	Kanbe et al			
	AC	5,815,343	09/1998	Ishikawa et al			
	AD	6,168,861	01/2001	Chen et al			
	AE	5,939,202	08/1999	Ataka et al			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	<del>AL 10-269548</del>	<del>10/9/98</del>	<del>Japan</del>			<input type="checkbox"/>	<input type="checkbox"/>
	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AR	<del>JOURNAL OF MAGNETISM AND MAGNETIC MATERIALS, 152 (1996), "Effects of Pt addition on the magnetic and crystallographic properties of Co-Cr-Pt thin film media", A. Ishikawa et al, pp. 265-273.</del>					
	AS	<del>Nakatani, Y. and Hayashi, N., IEEE Trans. Mag., 34(4), 1998, 1618-1620.</del>					
	AT	<del>Ikeda, Y., Sonobe, Y., Zeltzer, G., Yen, B., Takano, K., Do, H., Fullerton, E., and Rice, P., IEEE Trans. Mag., 37(4), 2001, 1583, 1585.</del>					
EXAMINER				DATE CONSIDERED			
<b>ABR</b>				<b>9-18-05</b>			

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-1027-02		SERIAL NO. <u>10/774,371</u>	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i> <u>(2) of (2)</u>				APPLICANT Y. TAKAHASHI et al		FILING DATE 2/10/04	
				GROUP <u>1773</u> <u>1762</u>			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL						<input type="checkbox"/> <input type="checkbox"/>
	AM						<input type="checkbox"/> <input type="checkbox"/>
	AN						<input type="checkbox"/> <input type="checkbox"/>
	AO						<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
<b>OTHER DOCUMENTS</b> (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR	<del>Lu, B., Klemmer, T., Khisroev, S., Howard, J., Litvinov, D., Roy, A., and Laughlin, D., IEEE Trans. Mag., 37(4), 2001, 1319-1321.</del>					
	AS	<del>Yamanaka, K., Hamamoto, T., Nakano, Y. and Miura, M., IEEE Trans. Mag., 37(4), 2001, 1599-1601.</del>					
	AT	<del>Futamoto, M., Honda, Y., Miyayama, Y., Itoh, K., Ide, H., and Maruyama, Y., IEEE Trans. Mag., 32(5), 1996, 3789-3794.</del>					
EXAMINER <u>AB/Blm</u>				DATE CONSIDERED <u>9-18-05</u>			

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.